

Benchtop XRF Machine

Compact ECO Series



Coating Thickness



Material Analysis

GERMAN TECHNOLOGY



Model	Compact Eco	Compact Eco Pin (Si-Pin)	Compact Eco SDD
Measuring Direction	Top to Bottom		
Applied Application	Coating Thickness Measurement on Metals, Gold & Silver Analysis in jewellery and alloys		
X-ray Tube	Min-focus, high performance, W-target, spot 0.2mm-0.8mm	Long Life, High efficiency tungsten target, air cooled	
High Voltage	50kV (1.2mA) Software Control Optimized	50kV / (1.2mA) programmable	
Detector	High resolution Gas Filled Prop Counter	High resolution Silicon Pin Detector	Silicon Drift Detector
Measurement Time	60 sec. to 180 sec.		
Collimator	0.3mmØ or 0.5mmØ, Optional four positions Collimator changer		
Sample Stage	Manual scissors type z-stage,		
Power Supply	230V AC, 50/60Hz, 120W / 100W		
Inside Chamber	375 x 350 x 255 mm (LxWxH)		
Dimension	630 x 430 x 420 mm (LxWxH)		
Weight (Approx)	45 kg		
Optional	Auto Z stage, Joy-Stick real operational movement, point & shoot, auto-focus facility		